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Sorting Category: 6.6.2 (Experimental)

Automated Analysis of Reflectometer Density Profiles on DIII-D[1] L. ZENG, E.J. DOYLE, W.A. PEEBLES, UCLA, T.C. LUCE, General Atomics — Over the last year the DIII-D reflectometer system has been further upgraded so as to operate for the first time as a "standard" diagnostic system on DIII-D, *i.e.*, with profile coverage throughout the discharge duration, and automated profile analysis. Specifically, an initial automated between-shots profile analysis capability has been implemented. The automatic analysis has proved robust for edge X-mode measurements, but is not yet as reliable for core O-mode measurements. In addition, the availability of analyzed profiles to end-users has been significantly improved in a modern multi-user environment, using the standard DIII-D "Reviewplus" and "GAprofiles" data viewing and fitting packages.

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☐ Prefer Oral Session
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Special instructions: Diagnostics, immediately following GW Watson

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